

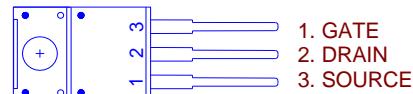
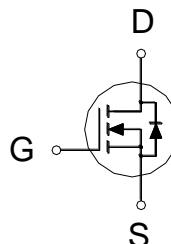
**NIKO-SEM**
**N-Channel Enhancement Mode  
Field Effect Transistor**
**P1650GTF**

TO-220F

Halogen-Free &amp; Lead-Free

**PRODUCT SUMMARY**

$V_{(BR)DSS}$	$R_{DS(ON)}$	$I_D$
500V	360m $\Omega$	16A

**ABSOLUTE MAXIMUM RATINGS ( $T_A = 25^\circ\text{C}$  Unless Otherwise Noted)**

PARAMETERS/TEST CONDITIONS	SYMBOL	LIMITS	UNITS
Drain-Source Voltage	$V_{DS}$	500	V
Gate-Source Voltage	$V_{GS}$	$\pm 30$	V
Continuous Drain Current <sup>2</sup>	$I_D$	16	A
		10	
Pulsed Drain Current <sup>1, 2</sup>	$I_{DM}$	60	A
Avalanche Current <sup>3</sup>	$I_{AS}$	9	
Avalanche Energy <sup>3</sup>	$E_{AS}$	410	mJ
Power Dissipation	$P_D$	56.8	W
		22.7	
Operating Junction & Storage Temperature Range	$T_j, T_{stg}$	-55 to 150	°C

**THERMAL RESISTANCE RATINGS**

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNITS
Junction-to-Case	$R_{\theta JC}$		2.2	°C / W
Junction-to-Ambient	$R_{\theta JA}$		62.5	

<sup>1</sup>Pulse width limited by maximum junction temperature.<sup>2</sup>Limited only by maximum temperature allowed<sup>3</sup> $V_{DD} = 50\text{V}$ ,  $L = 10\text{mH}$ , starting  $T_J = 25^\circ\text{C}$ **ELECTRICAL CHARACTERISTICS ( $T_J = 25^\circ\text{C}$ , Unless Otherwise Noted)**

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
<b>STATIC</b>						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0\text{V}$ , $I_D = 250\mu\text{A}$	500			V
Gate Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}$ , $I_D = 250\mu\text{A}$	2	2.7	4	
Gate-Body Leakage	$I_{GSS}$	$V_{DS} = 0\text{V}$ , $V_{GS} = \pm 30\text{V}$			$\pm 100$	nA

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Gate Voltage Drain Current	$I_{DSS}$	$V_{DS} = 500V, V_{GS} = 0V, T_C = 25^\circ C$			1	$\mu A$
		$V_{DS} = 400V, V_{GS} = 0V, T_C = 100^\circ C$			100	
Drain-Source On-State Resistance <sup>1</sup>	$R_{DS(ON)}$	$V_{GS} = 10V, I_D = 8A$		296	360	$m\Omega$
Forward Transconductance <sup>1</sup>	$g_{fs}$	$V_{DS} = 10V, I_D = 8A$		16		S
<b>DYNAMIC</b>						
Input Capacitance	$C_{iss}$	$V_{GS} = 0V, V_{DS} = 25V, f = 1MHz$		2707		$pF$
Output Capacitance	$C_{oss}$			236		
Reverse Transfer Capacitance	$C_{rss}$			17		
Total Gate Charge <sup>2</sup>	$Q_g$	$V_{DD} = 400V, I_D = 16A, V_{GS} = 10V$		59		$nC$
Gate-Source Charge <sup>2</sup>	$Q_{gs}$			17		
Gate-Drain Charge <sup>2</sup>	$Q_{gd}$			18		
Turn-On Delay Time <sup>2</sup>	$t_{d(on)}$	$V_{DD} = 250V, I_D = 16A, R_G = 25\Omega$		45		$nS$
Rise Time <sup>2</sup>	$t_r$			180		
Turn-Off Delay Time <sup>2</sup>	$t_{d(off)}$			130		
Fall Time <sup>2</sup>	$t_f$			100		
<b>SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS (<math>T_J = 25^\circ C</math>)</b>						
Continuous Current <sup>3</sup>	$I_S$				16	A
Forward Voltage <sup>1</sup>	$V_{SD}$	$I_F = 16A, V_{GS} = 0V$			1	V
Reverse Recovery Time	$t_{rr}$	$I_F = 16A, dI_F/dt = 100A / \mu S$		376		$nS$
Reverse Recovery Charge	$Q_{rr}$			5.2		$uC$

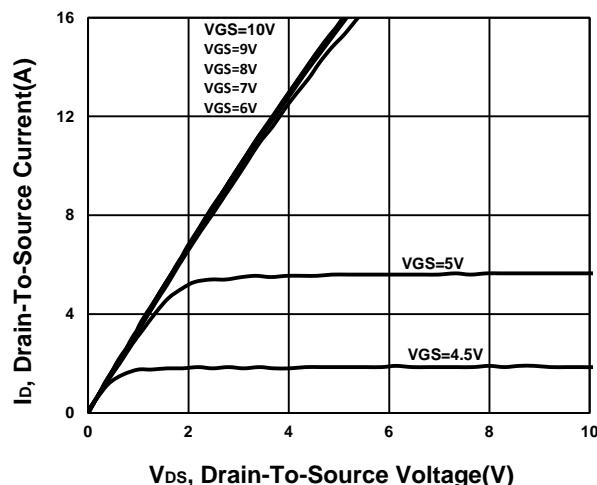
<sup>1</sup>Pulse test : Pulse Width  $\leq 300 \mu sec$ , Duty Cycle  $\leq 2\%$ .<sup>2</sup>Independent of operating temperature.<sup>3</sup>Pulse width limited by maximum junction temperature.

**NIKO-SEM**

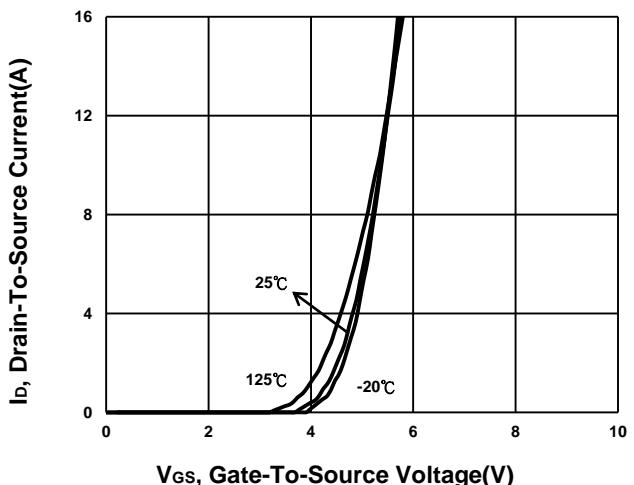
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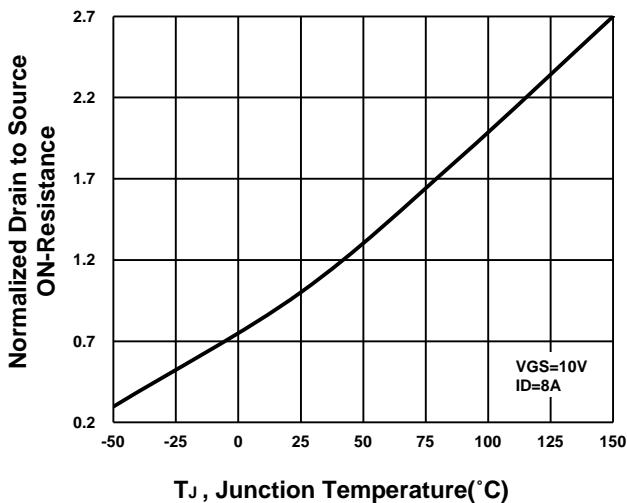
**Output Characteristics**



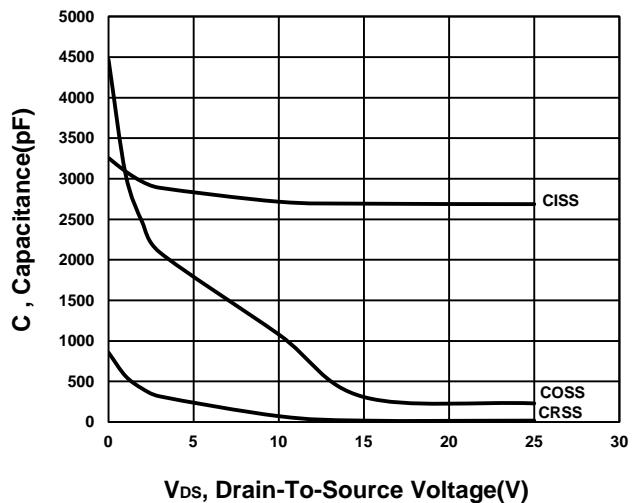
**Transfer Characteristics**



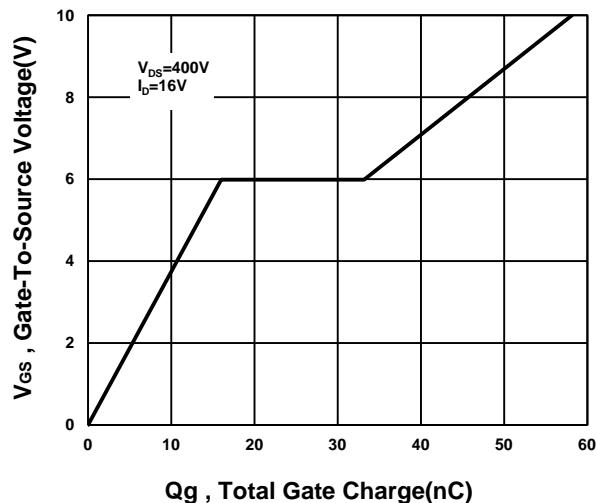
**On-Resistance VS Temperature**



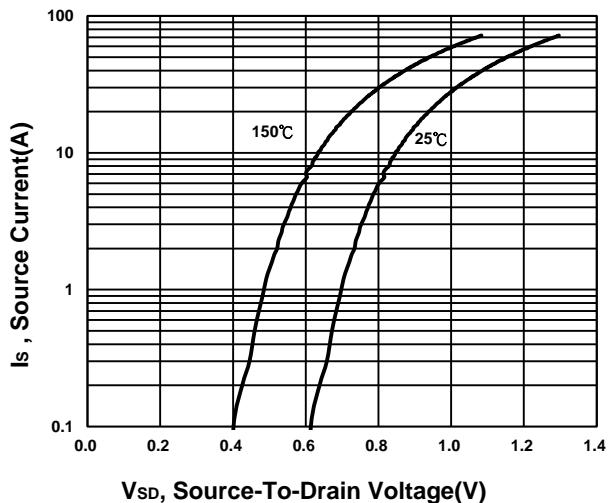
**Capacitance Characteristic**



**Gate charge Characteristics**



**Source-Drain Diode Forward Voltage**

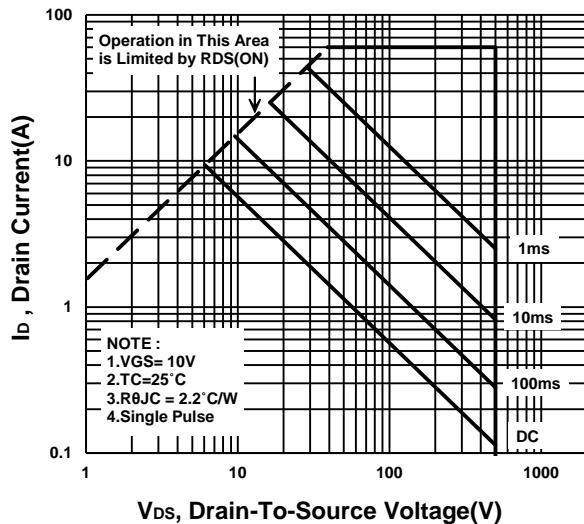


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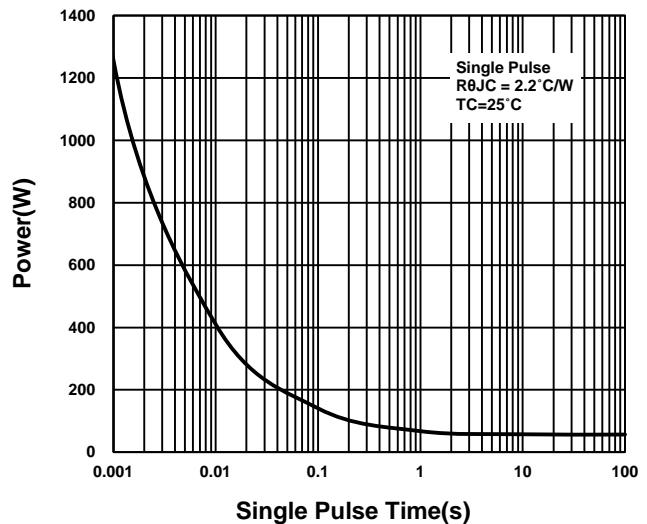
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### Safe Operating Area



### Single Pulse Maximum Power Dissipation



### Transient Thermal Response Curve

